

High-speed double diode**BAW56W****FEATURES**

- Very small plastic SMD package
- High switching speed: max. 4 ns
- Continuous reverse voltage: max. 75 V
- Repetitive peak reverse voltage: max. 85 V
- Repetitive peak forward current: max. 500 mA.

APPLICATIONS

- High-speed switching in e.g. surface mounted circuits.

DESCRIPTION

The BAW56W consists of two high-speed switching diodes with common anodes, fabricated in planar technology, and encapsulated in the very small plastic SMD SOT323 package

PINNING

PIN	DESCRIPTION
1	cathode (k1)
2	cathode (k2)
3	common anode

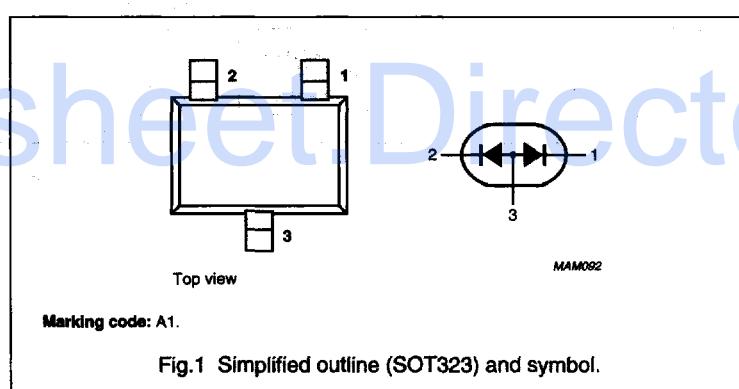


Fig.1 Simplified outline (SOT323) and symbol.

LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
Per diode					
V _{RRM}	repetitive peak reverse voltage		—	85	V
V _R	continuous reverse voltage		—	75	V
I _F	continuous forward current	single diode loaded; see Fig.2; note 1	—	150	mA
		double diode loaded; see Fig.2; note 1	—	130	mA
I _{FRM}	repetitive peak forward current		—	500	mA
I _{FSM}	non-repetitive peak forward current	square wave; T _j = 25 °C prior to surge; see Fig.4			
		t = 1 µs	—	4	A
		t = 1 ms	—	1	A
		t = 1 s	—	0.5	A
P _{tot}	total power dissipation	T _{amb} = 25 °C; note 1	—	200	mW
T _{stg}	storage temperature		-65	+150	°C
T _j	junction temperature		—	150	°C

Note

1. Device mounted on an FR4 printed-circuit board.

High-speed double diode**BAW56W****ELECTRICAL CHARACTERISTICS** $T_j = 25^\circ\text{C}$; unless otherwise specified.

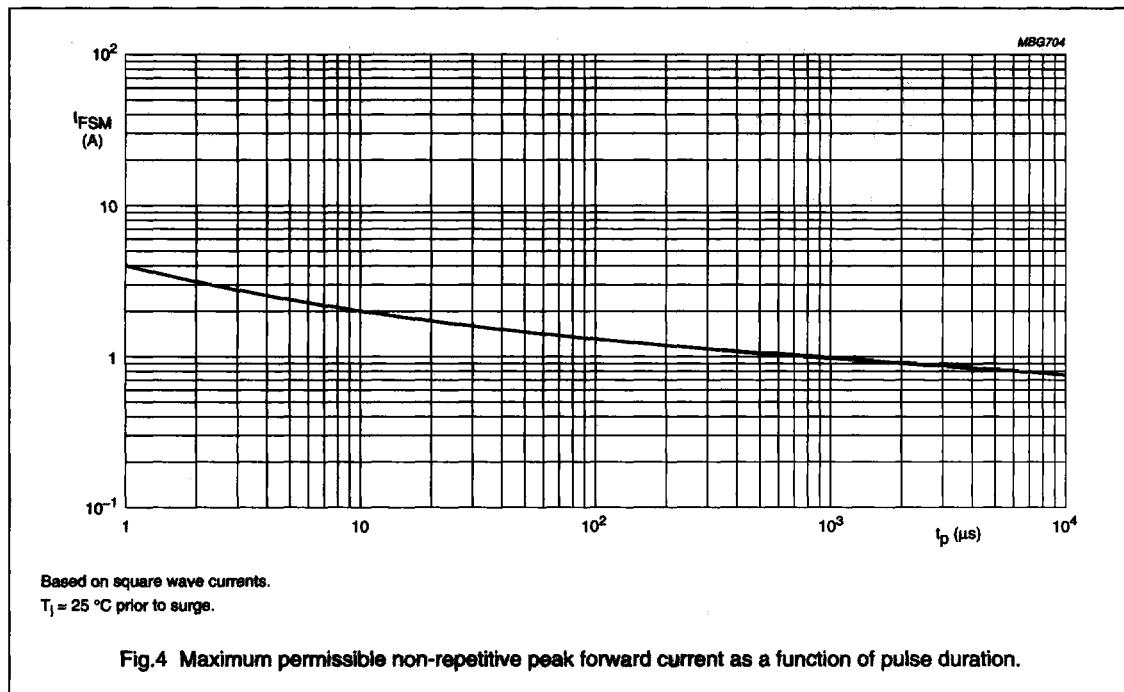
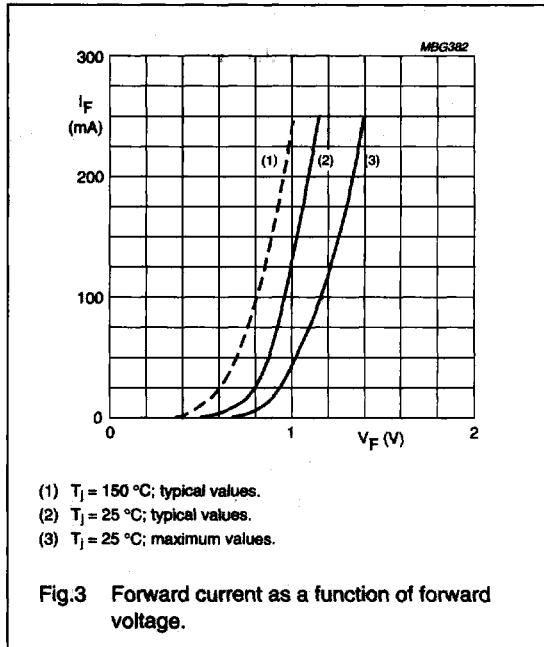
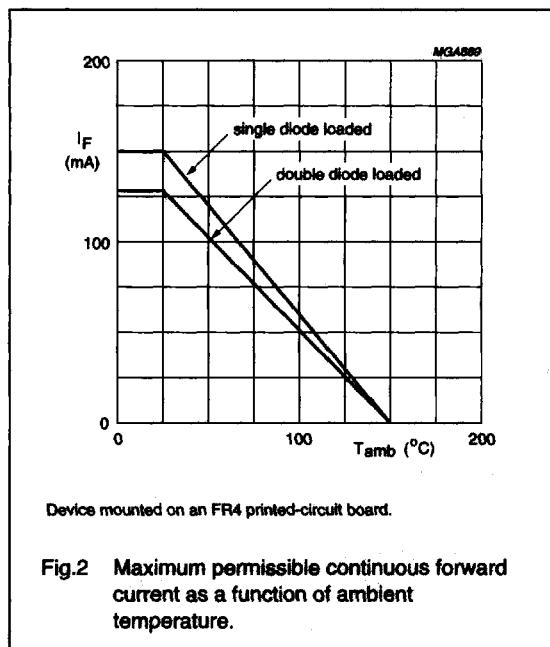
SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
Per diode					
V_F	forward voltage	see Fig.3 $I_F = 1 \text{ mA}$ $I_F = 10 \text{ mA}$ $I_F = 50 \text{ mA}$ $I_F = 150 \text{ mA}$	-	715 855 1 1.25	mV mV V V
I_R	reverse current	see Fig.5 $V_R = 25 \text{ V}$ $V_R = 75 \text{ V}$ $V_R = 25 \text{ V}; T_j = 150^\circ\text{C}$ $V_R = 75 \text{ V}; T_j = 150^\circ\text{C}$	-	30 1 30 50	nA μA μA μA
C_d	diode capacitance	$f = 1 \text{ MHz}; V_R = 0$; see Fig.6	-	2.0	pF
t_{rr}	reverse recovery time	when switched from $I_F = 10 \text{ mA}$ to $I_R = 10 \text{ mA}$; $R_L = 100 \Omega$; measured at $I_R = 1 \text{ mA}$; see Fig.7	-	4	ns
V_{fr}	forward recovery voltage	when switched from $I_F = 10 \text{ mA}$; $t_r = 20 \text{ ns}$; see Fig.8	-	1.75	V

THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	CONDITIONS	VALUE	UNIT
$R_{th j\text{-tp}}$	thermal resistance from junction to tie-point		300	K/W
$R_{th j\text{-a}}$	thermal resistance from junction to ambient	note 1	625	K/W

Note

1. Device mounted on an FR4 printed-circuit board.

High-speed double diode**BAW56W****GRAPHICAL DATA**

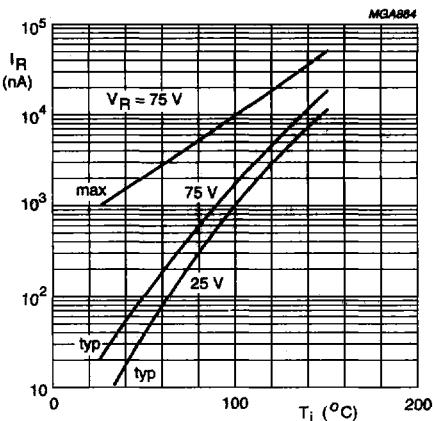
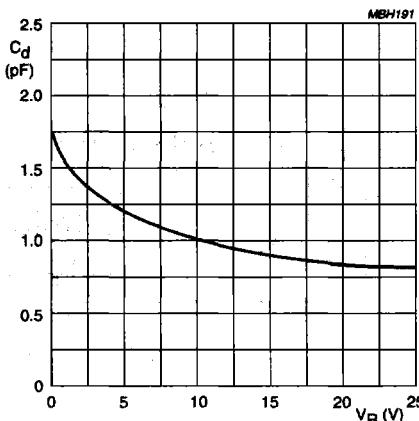
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Fig.5 Reverse current as a function of junction temperature.



$f = 1 \text{ MHz}; T_j = 25^\circ\text{C}$.

Fig.6 Diode capacitance as a function of reverse voltage; typical values.

High-speed double diode

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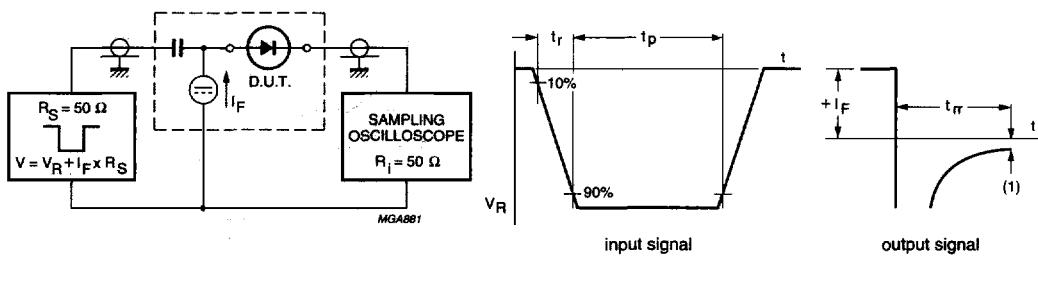
(1) $I_R = 1 \text{ mA}$.

Fig.7 Reverse recovery voltage test circuit and waveforms.

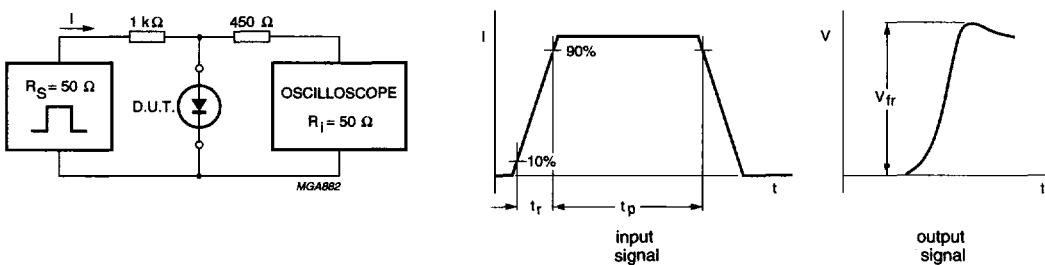


Fig.8 Forward recovery voltage test circuit and waveforms.